

Technical Datasheet

Graphene Field-Effect Transistor Chip: S10

General Description

The GFET chip from Graphenea delivers state-of-the-art graphene devices directly to the customer to allow application-driven research & development without the added burden of having to fabricate high-quality GFETs from the start.

The GFET-S10 chip from Graphenea provides 30 graphene Hall-bar devices distributed in a grid pattern on the chip. These devices can be used for Hall measurements as well as 4-probe and 2-probe measurements. There are varying graphene channel dimensions to allow investigation of geometry dependence on device properties, enabling immediate optimization.

Features

- State-of-the-art GFETs utilizing Graphenea's established high-quality graphene
- Devices not encapsulated ready for your functionalization
- Perfect platform device for new sensor research and development
- 30 individual GFETs per chip
- Mobilities typically in excess of $1000 \text{ cm}^2/\text{V}\cdot\text{s}$

Applications

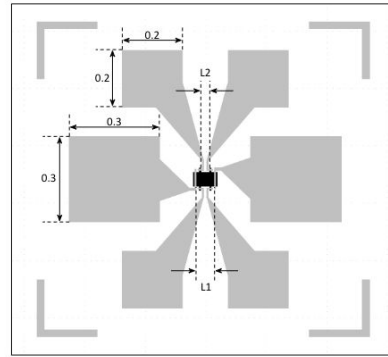
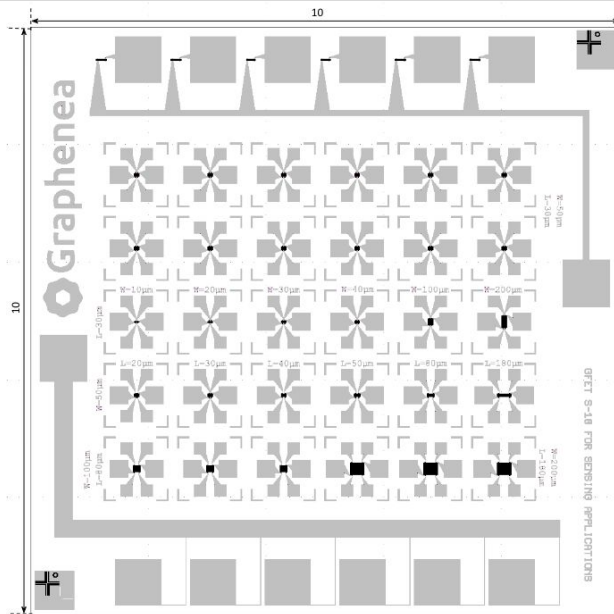
- Graphene device research
- Quantum transport
- Chemical sensors
- Magnetic sensors
- Gas sensors
- Photodetectors

Typical Specifications

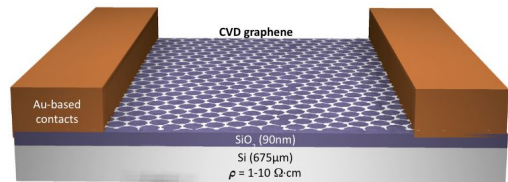
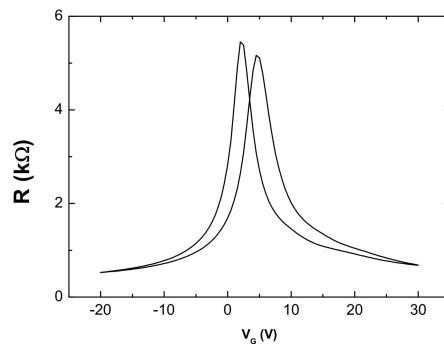
Chip dimensions	10 mm x 10 mm
Chip thickness	675 μm
Number of GFETs per chip	30
Gate Oxide thickness	90 nm
Gate Oxide material	SiO_2
Resistivity of substrate	1-10 $\Omega\cdot\text{cm}$
Metallization	Au contacts
Graphene field-effect mobility	$> 1000 \text{ cm}^2/\text{V}\cdot\text{s}$
Dirac point	$< 25 \text{ V}$
Number of graphene channels with integrity	$> 75 \%$

Absolute Maximum Ratings

Maximum gate-source voltage	$\pm 50 \text{ V}$
Maximum temperature rating	150 $^\circ\text{C}$
Maximum drain-source current density	$10^7 \text{ A}\cdot\text{cm}^{-2}$

GFET-S10 Layout

Channel geometries

Description	W (μm)	L1 (μm)	L2 (μm)	Quantity
Standard	50	30	60	12
Varying width	10	30	60	1
	20			1
	30			1
	40			1
	100			1
Varying length	50	20	50	1
		30	60	1
		40	70	1
		50	80	1
		80	110	1
		180	210	1
Large square	100	80	110	3
	200	180	210	3

Device cross-section

Typical characteristics


Transfer curve measured at source-drain voltage of 20mV, at room temperature and vacuum conditions on a device with $W=50 \mu\text{m}$, $L=60 \mu\text{m}$.